

Application/Control No.	Applicant(s)/Patent under Reexamination HAWTIN, BRIAN							
09/701,140								
Examiner	Art Unit							
Gina C Vu	1617							

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	(Assistant Examiner) (Date)					SPEENI PADMANABHAN							O.G.			O.G.		
					SUPERVISORY PATENT EXAMINER						Pri	Print Claim(s)			Print Fig.			
(Legal Instruments Examiner) (Date)					(Primary Examiner) (Date) 7 1 2 0						106	1 1			I N	1/A		
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